

# UTILITY PATENT APPLICATION TRANSMITTAL

Only for new nonprovisional applications under 37 CFR 1.53(b))

Attorney Docket No.

35.G2732

First Named Inventor or Application Identifier

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## APPLICATION ELEMENTS

MPEP chapter 600 concerning utility patent application contents.

## ADDRESS TO:

Commissioner for Patents  
Box Patent Application  
Washington, DC 20231

1. ☒ Fee Transmittal Form  
(Submit an original, and a duplicate for fee processing)
2. ☐ Applicant claims small entity status.  
See 37 CFR 1.27.
3. ☒ Specification Total Pages **43**
4. ☒ Drawing(s) (35 USC 113) Total Sheets **16**
5. ☒ Oath or Declaration Total Pages **2**
- a. ☒ Newly executed (original or copy)
- b. ☐ Copy from a prior application (37 CFR 1.63(d))  
(for continuation/divisional with Box 17 completed)  
**[Note Box 6 below]**
- i. ☐ **DELETION OF INVENTOR(S)**  
Signed Statement attached deleting  
inventor(s) named in the prior application, see  
37 CFR 1.63(d)(2) and 1.33(b).
6. ☒ Application Data Sheet. See 37 CFR 1.76

7. ☐ CD-ROM or CD-R in duplicate, large table or Computer  
Program (*Appendix*)
8. ☐ Nucleotide and/or Amino Acid Sequence Submission  
(if applicable, all necessary)
- a. ☐ Computer Readable Form (CRF)
- b. Specification Sequence Listing on:
- i. ☐ CD-ROM or CD-R (2 copies); or
- ii. ☐ paper
- c. ☐ Statements verifying identity of above copies

## ACCOMPANYING APPLICATION PARTS

9. ☒ Assignment Papers (cover sheet & document(s))
10. ☐ 37 CFR 3.73(b) Statement ☐ Power of Attorney  
(when there is an assignee)
11. ☐ English Translation Document (if applicable)
12. ☐ Information Disclosure ☐ Copies of IDS  
Statement (IDS)/PTO-1449 Citations
13. ☐ Preliminary Amendment
14. ☒ Return Receipt Postcard (MPEP 503)  
(Should be specifically itemized)
15. ☐ Certified Copy of Priority Document(s)  
(if foreign priority is claimed)
16. ☐ Other: \_\_\_\_\_

17. If a CONTINUING APPLICATION, check appropriate box and supply the requisite information:

☐ Continuation ☐ Divisional ☐ Continuation-in-part (CIP) of prior application No. \_\_\_\_/\_\_\_\_  
Prior application information: Examiner \_\_\_\_\_ Group/Art Unit: \_\_\_\_\_

For CONTINUATION OR DIVISIONAL APPS only: The entire disclosure of the prior application, from which an oath or declaration is supplied under Box 5b, is considered a part of the disclosure of the accompanying continuation or divisional application and is hereby incorporated by reference. The incorporation can only be relied upon when a portion has been inadvertently omitted from the submitted application parts.

## 18. CORRESPONDENCE ADDRESS

☒ Customer Number or Bar Code Label **05514** (Insert Customer No. or Attach bar code label here) or ☐ Correspondence address below

NAME

Address

City

State

Zip Code

Country

Telephone

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CLAIMS	(1) FOR	(2) NUMBER FILED	(3) NUMBER EXTRA	(4) RATE	(5) CALCULATIONS
	TOTAL CLAIMS (37 CFR 1.16(c))	19-20 =	0	X \$ 18.00 =	\$ 0.00
	INDEPENDENT CLAIMS (37 CFR 1.16(b))	2-3 =	0	X \$ 80.00 =	\$ 0.00
	MULTIPLE DEPENDENT CLAIMS (if applicable) (37 CFR 1.16(d))			\$270.00 =	\$ 270.00
				BASIC FEE (37 CFR 1.16(a))	\$ 710.00
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	TOTAL =				\$ 980.00

19. Small entity status

- a. ☐ A small entity statement is enclosed
- b. ☐ A small entity statement was filed in the prior nonprovisional application and such status is still proper and desired.
- c. ☐ Is no longer claimed.


20. ☒ A check in the amount of \$ 980.00 to cover the filing fee is enclosed.

21. ☒ A check in the amount of \$ 40.00 to cover the recordal fee is enclosed.

22. The Commissioner is hereby authorized to credit overpayments or charge the following fees to Deposit Account No. 06-1205:

- a. ☒ Fees required under 37 CFR 1.16.
- b. ☐ Fees required under 37 CFR 1.17.
- c. ☐ Fees required under 37 CFR 1.18.

**SIGNATURE OF APPLICANT, ATTORNEY, OR AGENT REQUIRED**

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DATE	November 9, 2000

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CORRESPONDENCE INFORMATION

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APPLICATION INFORMATION

Title Line One: CORRECTING METHOD FOR CORRECTING EXPOSURE DATA  
Title Line Two: USED FOR A CHARGED PARTICLE BEAM EXPOSURE SYSTEM

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Docket Number: 35.G2732  
Secrecy Order in Parent Appl.?: No

REPRESENTATIVE INFORMATION

Representative Customer Number: 5514

PRIOR FOREIGN APPLICATIONS

Foreign Application One: 11-353484  
Filing Date: 12-13-1999  
Country: JAPAN  
Priority Claimed: Yes

TITLE OF THE INVENTION

CORRECTING METHOD FOR CORRECTING EXPOSURE DATA USED FOR  
A CHARGED PARTICLE BEAM EXPOSURE SYSTEM

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BACKGROUND OF THE INVENTION

Field of the Invention

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10 The present invention relates to a multi-type charged  
particle beam exposure system which draws a pattern by a  
plurality of charged particle beams, an exposing method  
therefor, and a manufacturing method for manufacturing a  
device utilizing the exposing method. More particularly,  
15 the present invention relates to a charged particle beam  
exposure system, an exposing method therefor, and a  
manufacturing method for manufacturing a device utilizing  
the exposing method, the method permitting a proximity  
effect correction to be performed rapidly and appropriately,  
and permitting a correction, for eliminating variations  
20 among charged particle beams irradiated, to be performed at  
a predetermined timing, when drawing a pattern on a  
substrate by charged particle beams.

Description of the Related Art

25 In recent years, as means for drawing a micro-pattern  
on a specimen such as a semiconductor wafer or a mask

substrate, an electron beam lithography system is used. In this system, however, the influence of a so-called proximity effect that causes the widening or narrowing of a pattern by backward-scattered electrons constitutes a problem.

5 One effective method for correcting the proximity effect is a correcting method for correcting an irradiation dose. As a method for determining the optimum irradiation dose, (a) a method using matrices (M. Parikhh, J. App. Phys. 19, p. 4371, p. 4378, p. 4383 (1979), (b) a method which  
10 uses a simple approximate solution as a formula (e.g., J. M. Parkovich, Journal of Vacuum Science & Technology B4, p. 159 (1986), or the like has been used.

The method (a) is a method wherein the relationship  
15 between the irradiation dose and the photosensitivity at each position is represented by a matrix, and the optimum irradiation dose at each position is found by obtaining the inverse matrix of the above-mentioned matrix. The advantage of this method is that the accurate optimum irradiation dose can be found if the size of a pattern, based on which the  
20 irradiation dose is set, is sufficiently reduced. On the other hand, the drawback thereof is that an enormous amount of calculation time is required. For example, in order to perform a correction with respect to all LSI chips being used directly for the drawing, it takes hundreds to  
25 thousands of hours.

The method (b) is a method wherein an approximate value  $D'$  is calculated using the following formulae (1) and (2)

$$D' = C / (1/2 + \eta U) \quad (1)$$

$$U = (1/\pi) \int \exp \{-(x-x')^2 - (y-y')^2\} dx' dy' \quad (2)$$

5 Here,  $C$  is a constant,  $\eta$  is the photosensitivity ratio of a resist of forward scattering of an electron beam and that by backward scattering. With regard to the integration range of the parameter  $U$ , the evaluation points of the irradiation dose are set to be  $(x, y)$ , and the integration is performed for rectangles existing within a circle which has a center  $(x, y)$ , and which has a radius two to three times larger than the backward-scattering radius, or for rectangles, some of which exist within the circle. However, even though such an approximate solution is used, it takes 10 several hours to perform a correction with respect to all LSI chips being used directly for the drawing. 15

Furthermore, in a multi-type charged particle beam exposure system, which draws a pattern by a plurality of charged particle beams, it is difficult to uniformly 20 maintain the irradiation dose of all of the charged particle beams, because of influences of heat generated by charged particle beams irradiating a substrate.

As described above, the calculation time for correcting a proximity effect requires at least several hours. On the 25 other hand,  $\eta$ , a parameter for the calculation for the

proximity effect correction, a backward-scattering radius, and the like, are varied depending on a resist applied to a wafer or a film material on the surface of a wafer. It is, therefore, necessary to determine the parameter (such as  $\eta$  and the backward-scattering radius) for achieving the optimum proximity effect. For this purpose, the step of recalculating the correction of a proximity effect by changing the parameter, and the step of actually exposing the wafer using the recalculated proximity effect correction and then evaluating the result obtained, are performed repeatedly. This means that the electron beam lithography system is exclusively employed for tens of hours to determine the parameter. This results in a reduction in the availability of the system.

Moreover, in a multi-type charged particle beam exposure system which draws a pattern by a plurality of charged particle beams, in order to achieve an exposure with a uniform irradiation dose by eliminating variations in the irradiation dose among a plurality of charged particle beams, for example, a calibration (correction) for changing duties among the beams is indispensable.

#### SUMMARY OF THE INVENTION

Accordingly, it is an object of the present invention

to solve the above-described problems associated with the conventional art.

In accordance with a first aspect, the present invention provides a charged particle beam exposure system which draws a pattern on an object to be exposed by a plurality of charged particle beams. This system comprises (a) a storage device storing (i) standard dose data for controlling the irradiation of charged particle beams to an object to be exposed, (ii) plural pieces of proximity effect correction data for correcting the irradiation of the charged particle beams for each incidence position with respect to the object to be exposed, in order to reduce the influence of a proximity effect, and (iii) calibration data for correcting variations in the irradiation dose among a plurality of the charged particle beams; and (b) a controller for controlling the irradiation of each of the charged particle beams, based on the standard dose data, the proximity effect correction data, and the calibration data.

The standard dose data preferably include bit map data which are determined depending on the pattern to be exposed.

Also, the standard dose data may include the data defining the bit map data and a ratio of the irradiation time with respect to the non-irradiation time.

Preferably, the present invention, in this aspect, includes means for obtaining the calibration data by



measuring variations in the irradiation dose among a plurality of the charged particle beams. The above-mentioned obtaining means may include a Faraday cup.

The present invention, in this aspect, preferably includes means for selecting one piece of data suitable for the proximity effect correction with respect to the standard dose data, from plural pieces of the proximity effect correction data stored in the memory device.

In accordance with a second aspect, the present invention provides a method for correcting exposure data for drawing a pattern on an object to be exposed by a plurality of charged particle beams, comprising the step of creating standard dose data for each irradiation position of the charged particle beams in order to expose a standard pattern on the object to exposed; the step of creating or renewing a plurality of proximity effect correction data for each irradiation position, depending on conditions of the object to be exposed; the step of selecting any one piece of the proximity effect correction data, from plural pieces of the proximity effect correction data for each irradiation position; the step of performing a proximity effect correction with respect to the standard dose data based on the selected data, and exposing a pattern on the object to be exposed; the step of evaluating the exposed pattern, and judging whether the selected one piece of proximity effect

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correction data is the optimum data for controlling the standard dose data; the step of determining the optimum proximity effect correction data for controlling the standard dose data in accordance with the judgment; the step of measuring, by a sensor, the irradiation dose of the charged particle beams from each element electron optical system, the irradiation dose having been subjected to a correction by the proximity effect correction data; and the step of determining the calibration data of each of the element electron optical systems, based on the irradiation dose measured by the above-mentioned measuring.

Whether the selected one piece of proximity effect correction data is the optimum data for controlling the standard dose data is preferably judged by comparing the exposed pattern and the standard pattern by a visual inspection.

Also, whether the selected one piece of proximity effect correction data is the optimum data for controlling the standard dose data is preferably judged by evaluating means for comparing the exposed pattern and the standard pattern.

Preferably, the proximity effect correction data is data not depending on the pattern to be exposed, but data depending on the conditions of the object to be exposed.

The conditions are preferably determined as at least

one parameter among the fundamental conditions of the object to be exposed, the resist material, and a backward-scattering radius.

The above-mentioned sensor used in the measuring step  
5 may include a Faraday cup.

The present invention, in a third aspect, provides a method for manufacturing a device, comprising the step of providing an exposure system as discussed above; the step of exposing a pattern on a wafer using the exposure system; and  
10 the step of assembling the device by processing the wafer on which the pattern has been exposed.

Further objects, features and advantages of the present invention will become apparent from the following description of the preferred embodiments with reference to  
15 the attached drawings.

#### BRIEF DESCRIPTION OF THE DRAWINGS

Fig. 1 is a schematic diagram showing an electron beam  
20 exposure system in accordance with a preferred embodiment of the present invention;

Figs. 2A and 2B are diagrams showing the particular construction of a correction electron optical system;

Figs. 3A and 3B are diagrams showing one deflector  
25 drawn from deflectors formed in a blanker array (BA);

Fig. 4 is a diagram showing a blanker array, as viewed downward;

Fig. 5 is a diagram for explaining first and second electron optical system arrays;

5 Fig. 6 is a diagram for explaining the functions of a correction electron optical system;

Fig. 7 is a block diagram showing the construction of the control system of the electron beam exposure system shown in Fig. 1;

10 Figs. 8A to 8D are diagrams for explaining the principles of exposure by the electron beam exposure system shown in Fig. 1;

Fig. 9 is a block diagram showing the construction of the system including an exposure system;

15 Fig. 10 is a block diagram for explaining the construction of a blanker array (BA) control circuit;

Fig. 11 is a flowchart for explaining the flow of the evaluation processing for establishing exposure correction information;

20 Fig. 12 is a flowchart for explaining the calibration procedure for calibration of an element electron beam optical system;

25 Fig. 13 is a representation showing the relationship of the drawing position with respect to the correction exposure information and the calibration data;

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Fig. 14 is a flowchart showing the processing of a data controller and a processing unit;

Fig. 15 is a block diagram showing a flowchart of manufacturing a micro device (e.g., a semiconductor chip such as an IC and LSI, a liquid crystal panel, a CCD, a thin-film magnetic head, a micromachine, or the like); and

Fig. 16 is a flowchart showing the particular flow of wafer processing in the flowchart shown in Fig. 15.

#### DESCRIPTION OF THE PREFERRED EMBODIMENTS

As one example of a charged particle beam exposure system, a multi-type electron beam exposure system which draws a pattern by using a plurality of charged particle beams will be described below. The present invention can be applied not only to an electron beam exposure system, but also, for example, to an ion beam exposure system.

Fig. 1 shows an electron beam exposure system in accordance with a preferred embodiment of the present invention. In Fig. 1, reference numeral 1 denotes an electron gun comprising a cathode 1a, a grid 1b, and an anode 1c. The electrons emitted from the cathode 1a form a crossover image as an electron source ES between the grid 1b and the anode 1c.

Electron beams emitted from the electron source ES

irradiate a correction electron optical system 3 via condenser lens 2. The condenser lens 2 is constructed of, for example, three opening electrodes.

As shown in Fig. 2B, the correction electron optical system 3 is constructed of an aperture array AA, a blanker array BA, correction electron optical system units LAU, and a stopper array SA which are disposed in sequence along the optical axis AX from the electron gun 1 side. Hereafter, the correction electron optical system 3 will be described in detail.

Returning to Fig. 1, the correction electron optical system 3 forms a plurality of intermediate images, and each of the intermediate images is reducedly projected onto the substrate 5 of a wafer or the like by a demagnification electron optical system 4 which is described hereafter. Thereby, a plurality of electron source images having the same shape is formed on the substrate 5. The correction electron optical system 3 forms the above-mentioned intermediate images so as to correct aberration occurring when a plurality of the intermediate images is reducedly projected onto the substrate 5 via the electron optical system 4.

The demagnification electron optical system 4 is constructed of a symmetrical magnetic doublet constituted by a first projection lens 41 and a second projection lens 42,

and a symmetrical magnetic doublet constituted by a first projection lens 43 and a second projection lens 44. Letting the focal length of the first projection lens 41 (43) be  $f_1$ , and that of the second projection lens 42 (44) be  $f_2$ , the distance between the two projection lenses is  $f_1 + f_2$ .

The object point on the optical axis AX is situated at the focal position of the first projection lens 41 (43), and the image point thereof is formed at the focus of the second projection lens 42 (44). This image is reduced into  $-f_2/f_1$ . The exposure system 100 is determined so that two lens magnetic fields act in the reverse directions to each other. Therefore, in theory, Seidel aberration, and chromatic aberration with respect to rotation and magnification are cancelled, apart from five others aberrations: spherical aberration, isotropic astigmatism, isotropic coma aberration, image surface curve aberration, and axial chromatic aberration.

Reference numeral 6 denotes a deflector deflecting a plurality of electron beams from the correction electron optical system 3, and deflecting a plurality of the electron images on the substrate 5 in X and Y directions by substantially the same amount of displacement. Although it is not shown in the figure, the deflector 6 is constructed of a main deflector used when the deflection width is large, and an auxiliary deflector used when the deflection width is

small. The main deflector is an electromagnetic type deflector, and the auxiliary deflector is an electrostatic type deflector.

Reference numeral 7 denotes a dynamic focus coil which corrects the displacement of the focal position of the electron source due to deflection aberration occurring when the deflector 6 is actuated. Reference numeral 8 denotes a dynamic astigmatism correction coil which corrects the astigmatism of the deflection aberration generated by the deflection.

Reference numeral 9 denotes a  $\theta$  - Z stage which places the substrate 5 thereon, and which can be moved in the optical axis AX (Z axis) direction and in the rotational direction about the Z axis, and a sensor 10 fixed to the stage 9 includes, for example, a Faraday cup. The sensor 10 individually detects the irradiation dose of each of the charged particle beams incident on the stage 9.

Reference numeral 11 denotes an X - Y stage, which mounts the  $\theta$  - Z stage, and which can be moved in the X - Y directions orthogonal to the optical axis AX (Z axis).

Next, the construction of the correction electron optical system 3 will be described with reference to Figs. 2A and 2B. As described above, the correction electron optical system 3 is constructed of the aperture array AA, the blanker array BA, the correction electron optical system



units LAU, and the stopper array SA.

Fig. 2A is a diagram showing the correction electron optical system 3, as viewed from the electron gun 1 side, and Fig. 2B is a cross-sectional view taken along the line A-A' of Fig. 2A.

As shown in Fig. 2A, the aperture array AA has a structure in which a plurality of apertures are provided in the substrate, and divides an electron beam from the condenser lens 2 into a plurality of electron beams. The blanker array BA is constructed by forming a plurality of deflectors on one substrate, the deflectors each individually deflecting each of the electron beams formed in the aperture array.

Figs. 3A and 3B are diagrams showing one deflector drawn from a plurality of the deflectors formed in a blanker array BA. Fig. 4 is a diagram showing a blanker array BA, as viewed downward. As shown in Figs. 3A and 3B, the blanker array BA is constructed of the substrate 31 having a plurality of apertures AP formed therein and a pair of electrodes across each of the apertures. The blanker array BA has blankers 32 each having a deflecting function, and wiring for individually turning the blankers 32 on/off.

The correction electron optical system LAU is constructed of a first electron optical system array LA1 which is an electron lens array formed by two-dimensionally

arranging a plurality of electron lenses on the identical plane, and a second electron optical system LA2.

Fig. 5 shows the first electron optical system array LA1. Each of the first electron optical system array LA1 has an upper electrode plate UE, an intermediate electrode plate CE, and a lower electrode plate LE, in each of which a plurality of doughnut-shaped electrodes corresponding to a plurality of the apertures is arranged. Each of the first electron optical system arrays LA1 is constructed by laying up these three electrode plates through the intermediary of insulating materials.

The upper, intermediate, and lower doughnut-shaped electrode plates, which have equal X - Y coordinates, constitute one electron lens (a so-called unipotential lens) UL. The upper doughnut-shaped electrode plate of each of the electron lenses UL is connected to the LAU control circuit 112 by the common wiring W1, and the lower doughnut-shaped electrode plate of each of the electron lenses UL is connected to the LAU control circuit 112 by the common wiring W3. An acceleration potential of electron beams is applied across the upper doughnut-shaped electrode plate and the lower doughnut-shaped electrode plate. An appropriate potential is supplied from the LAU control circuit 112 to the intermediate doughnut-shaped electrode plate of each of the electron lenses via individual wiring W2. Thereby, it

is possible to set the electron optical power (focal length) of each of the electron lenses to a desired value. The second electron optical system array LA2 has the same structure and functions as those of the first electron optical system array LA1.

As shown in Fig. 2B, in the correction electron optical system unit LAU, the electron lenses of the first electron lens array LA1 and those of the second lens array LA2, each of which has an equal X - Y coordinate, constitute an element electron optical system EL.

The aperture array AA is situated at substantially the front side focal position of each of the element electron optical systems EL. Each of the element electron optical systems EL, therefore, forms an intermediate image of the electron source ES by each of the divided electron beams, at substantially the rear side focal position. Here, in order to correct the image surface curve aberration occurring when the intermediate images are reducedly projected upon the substrate 5 via the demagnification electron optical system 4, the electron optical power of the electron lens is adjusted by adjusting the potential applied to the intermediate doughnut-shaped electrode for each element electron optical system EL, whereby the formation position of the intermediate images is adjusted.

The stopper array SA has a structure wherein a

plurality of apertures is formed in the substrate, as in the case of the aperture array AA. The electron beam deflected by the blanker array BA is irradiated out of the aperture of the stopper array SA corresponding to the electron beam, and is blocked by the substrate.

Next, the function of the correction electron optical system 3 will be described using Fig. 6. The electrons emitted from the electron source ES pass through the condenser lens 2, and thereby, electron beams substantially parallel to each other are formed. These substantially parallel electron beams are divided into a plurality of electron beams by the aperture array AA having a plurality of the apertures. Each of the divided electron beams is made incident on the element electron optical systems EL1 through EL3, and forms intermediate images img1 through img3 of the electron source ES at substantially the front side focal position of each of the element electron optical systems. Each of the intermediate images is projected upon the substrate 5 as an object to be exposed via the demagnification electron optical system 4.

Here, in order to correct the image surface curve aberration (the deviation of the actual image-forming position from the ideal image-forming position on the substrate 5 in the direction of the optical axis of the demagnification system) occurring when a plurality of the

intermediate images is reducedly projected upon the object to be exposed, the optical properties of a plurality of the element electron optical systems are individually set, and the formation positions of the intermediate images in the direction of the optical axis are made different for each element electron optical system, as described above.

The blankers B1 through B3 of the blanker array BA and the stoppers S1 through S3 of the stopper array SA individually control whether each electron beam is to be emitted onto the substrate 5. In Fig. 6, since the blanker B3 has been turned on, the electron beam which would otherwise form the intermediate image img3 does not pass through the aperture S3 of the stopper array SA, and is blocked by the substrate of the stopper array SA.

Fig. 7 shows the construction of the control system of the electron beam exposure system 100 shown in Fig. 1. BA control circuit 111 is a control circuit for individually controlling turning on/off of each blanker of the blanker array BA. The construction and function thereof will be described in detail hereafter. Here, LAU control circuit 112 is a control circuit for controlling the focal length of the electron lens EL constituting the lens array unit LAU, D\_STIG control circuit 113 is a circuit for controlling the dynamic astigmatism correction coil 8 to correct the astigmatism of the demagnification electron optical system 4,

and D\_FOCUS control circuit 114 is a circuit for controlling the dynamic focus coil 7 to adjust the focus of the demagnification electron optical system 4. A deflection control circuit 115 is a control circuit for controlling the deflector 6, and an optical property control circuit 116 is a circuit for adjusting the optical properties (magnification and distortion) of the demagnification electron optical system 4. A reflected electron detection circuit 117 is a circuit for computing the amount of reflected electrons from the signals from a reflected electron detector 12.

A stage drive control circuit 118 is a control circuit which drivingly controls the  $\theta$  - Z stage 9 and also drivingly controls the X - Y stage 11 in cooperation with a laser interferometer LIM for detecting the position of the X - Y stage 11.

An auxiliary controller 120 reads out exposure control data stored in a memory or other storage device 121 via an interface 122, and thereby controls control circuits (control elements) 111 through 116 and 118, and controls a reflected electron detection circuit 117. A main controller 123 exercises control over the entire electron beam exposure system 100.

Next, the schematic operation of the electron beam exposure system 100 shown in Fig. 1 will be described with

reference to Fig. 7.

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Auxiliary controller 120 reads out the exposure control data from the memory 121, extracts deflection control data (e.g., the main deflector standard position, the auxiliary deflector standard position, main deflection stage follow-up data, deflection control data) as control data for controlling the deflector 6 from the above-mentioned exposure control data, and provides these deflection control data to the deflection control circuit 115. At the same time, the auxiliary controller 120 extracts blanker data and data for correcting the control over the blankers as control data for controlling each blanker of blanker array BA from the above-mentioned exposure control data, and provides these data to the BA control circuit 111. As shown in Fig. 10, the data provided here are stored in a basic dose data memory 1010 and a first correction factor memory 1020 of the BA control circuit 111.

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A deflection control circuit 115 controls the deflector 6 based on the deflection control data, and thereby deflects a plurality of the electron beams. At the same time, the BA control circuit 111 controls each blanker of the blanker array BA, and thereby turns each blanker on/off depending on the pattern to be drawn. When scanning the substrate 5 by a plurality of the electron beams in order to draw a pattern on the substrate 5, the X - Y stage 11 is continuously moved

in the Y direction, and a plurality of the electron beams is deflected by the deflector 6 so as to follow the movement of the X - Y stage.

As shown in Figs. 8A to 8D, each of the electron beams performs scan exposure with respect to a corresponding element exposure field (EF) on the substrate 5. This electron beam exposure system is designed so that an element exposure field (EF) by each of the electron beams is two-dimensionally contiguous to each other, and hence, a subfield (SF) constructed of a plurality of element exposure fields (EF) is exposed at once. In the example shown in Figs. 8A to 8D, one element exposure field (EF) is constituted by a matrix having 8x8 elements. Each element of this matrix indicates the field (position) which the electron beam deflected by the deflector 6 irradiates on the substrate 5. More specifically, one element exposure field (EF) constituted of the matrix having 8x8 elements is scanned in the order indicated by the arrow in Figs. 8A to 8D.

After one subfield (SF1) has been exposed, the auxiliary controller 120 instructs the deflection control circuit 115 to deflect, by the deflector 6, a plurality of electron beams in the direction (x direction) orthogonal to the scanning direction (y direction) of the X - Y stage 11 during scan exposure, so that the next subfield is exposed.



With such a change of a subfield, aberrations, when each electron beam is reducedly projected via the demagnification electron optical system, are also changed. Accordingly, the auxiliary controller 120 instructs the LAU control circuit 112, D\_STIG control circuit 113, and D\_FOCUS control circuit 114 to adjust the lens array unit LAU, the dynamic astigmatism correction coil 8, and the dynamic focus coil 7, so as to correct for the changed aberration.

After the subfield has been changed, a second subfield (SF2) is exposed by again performing the exposure with respect to the corresponding element exposure field (EF) by a plurality of the electron beams. In this manner, as shown in Figs. 8A to 8D, by performing the exposure of the subfields SF1 through SF6 in sequence, the exposure of a main field (MF) constituted of subfield 1 through subfield 6 arranged in the direction (x direction) orthogonal to the scanning direction (y direction) of the X - Y stage 11 during the scan exposure, is completed.

After the exposure of the first main field (MF1) has been thus completed, the auxiliary controller 120 instructs the deflection control circuit 115 to deflect in sequence a plurality of the electron beams toward main fields (MF2, MF3, MF3, MF4) sequentially arranged in the scanning direction (y direction) of the X - Y stage 11, and performs the exposure thereof. Thereby, as shown in Figs. 8A to 8D, the exposure

of a stripe  $\delta$  field (STRIPE 1) constituted of main fields  
(MF2, MF3, MF3, MF4) is performed. Then, the auxiliary  
controller 120 instructs the stage drive control circuit 118  
to steppingly move the X - Y stage in the x direction, and  
5 performs the exposure of a next stripe  $\delta$  field (STRIPE 2).

Fig. 9 shows the construction of a system including the  
exposure system. This system comprises the electron beam  
exposure system 100 shown in Fig. 1, and a computer 200  
connected to the electron beam system 100 via a  
10 communication cable 210. The computer 200 acquires exposed  
pattern data from, for example, other computers via  
communication lines 220, creates exposure control data  
suitable for the electron beam exposure system 100, based on  
this exposed pattern data, and provides these data to the  
15 electron beam exposure system 100 via the communication  
cable 210.

More specifically, the computer 200 acquires exposed  
pattern data from other computers via communication cable  
210, and stores them in a storage section 201. The exposed  
20 pattern data may be acquired from the memory medium (e.g., a  
magnetic tape, disk, or the like) in which the exposure  
pattern data is stored.

Next, the computer 200 creates a plurality of control  
data for controlling the electron beam exposure system 100  
25 (e.g., dot control data or dose control data for controlling

blankers, deflection control data for controlling the deflector, etc.) based on the exposed pattern data. The control data created here includes standard dose data as basic exposure information.

5       The "standard dose data" represents information constituting the basis of the drawing information depending on a pattern to be exposed, based on which the opening and closing of a blanker is controlled. Specifically, the standard dose data includes the construction of bit map data ("0" or "1"), or the data (duty) defining a bit map and the opening and closing times (i.e., the ratio of the irradiation time with respect to the non-irradiation time) of the blankers.

10       The irradiation light emitted by the electron gun 1a has a certain irradiation intensity, and is capable of controlling irradiation energy so as to be a desired value in accordance with the duty of the blanker. The term "proximity effect correction" hereafter referred to, is to perform a correction wherein the duty, which does not depend on the drawing pattern, but which is defined by the standard dose data in consideration of the conditions which an object to be exposed has, is increased or decrease  $\delta$ , and to thereby realize the optimum irradiation (exposure) state for the object to be exposed.

25       Next, the computer 200, in a correction exposure

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information generator 203, creates correction exposure  
information for performing a proximity effect correction for  
each irradiation position with respect to the standard dose  
data generated by a control data generator 202. The  
5 correction exposure information is correction data not  
depending on an exposed pattern, and is created in  
consideration of the backward-scattering radius when a  
pattern is exposed on a surface to be exposed, the  
difference in a resist material and foundation conditions,  
10 and the like, as parameters. The resist information and the  
foundation information 204, which are inputted from outside  
terminals and stored in the computer 200, may be referred to  
as the resist information and foundation information.  
Further, information on exposed patterns may also be  
15 considered. The standard dose data with respect to which a  
proximity effect correction has been performed is subjected  
to a correction of duty thereof.

In a calibration data generator 205 of the exposure  
system 100, mutual correction data (calibration data), among  
20 charged particle beams for correcting variations among  
irradiation beams generated under the influence of heating  
caused by the irradiation by the electron beams, are created.

In the exposure system 100, this calibration data is  
determined based on the results individually detected with  
25 respect to the irradiation dose for each incident electron

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beam by means of a sensor (including a Faraday cup) fixed on the stage 9 (Fig. 1) for mounting an object to be exposed, and these results are stored in the second correction factor memory 1030 shown in the BA control circuit section 111 in Fig. 10.

Fig. 10 shows an example of the BA control circuit (blanker array control circuit) 111 described with reference to Fig. 7. The blanker array control circuit 111 comprises a storage device, including a basic dose data memory 1010 which stores the standard dose data as basic exposure information; the first correction factor memory 1020 which stores correction exposure information including the proximity effect correction factor; the second correction factor memory 1030 which stores calibration information for performing a correction (calibration) with respect to variations among a plurality of irradiation beams. The blanker array control circuit 111 also comprises a data controller 1040 which controls the selecting of data for performing a proximity effect correction and a calibration among irradiation beams with respect to the standard dose data, in order to realize an appropriate exposure for an object to be exposed; a computing element 1050 for computing drawing dose data in order to draw a pattern on the object to be exposed based on data selected as the most appropriate correction exposure information and calibration information

in accordance with the above-described result of the selection control; a drawing dose data memory 1060 for temporarily storing the output of the computing results; and a driver 1070 for driving blankers based on the drawing dose data.

Fig. 11 shows a flowchart of the evaluation in relation to the creation of data and the selection and determination of the correction exposure information. In step S1101, the standard dose data are created, which include the base exposure information in the control data generator 202 in the computer 200, and are stored in the basic dose memory 1010 of the BA control circuit section 111.

In step 1102, correction exposure information, including a proximity effect correction factor, is created in the correction exposure information generator 203, and is stored in the proximity effect correction factor memory 1020.

In step 1103, a pattern is drawn based on the standard dose data created in step 1101.

In step 1104, whether a proximity effect collection is necessary is judged based on the pattern drawn. If a proximity effect collection has been judged to be unnecessary, the evaluation is completed (S1105). On the other hand, if the proximity effect collection is judged to be necessary, the processing proceeds to step 110, one piece of correction exposure information is selected from the

correction exposure information stored in the first  
correction factor memory 1020 (S1106), and a pattern is  
drawn based on the dose data considering the correction  
exposure information (S1107). This pattern is referred to  
as a "corrected pattern".

In step S1108, the corrected pattern is evaluated, and  
in step S1109, whether the correction exposure information  
selected in step S1106 has been appropriate, and whether the  
corrected pattern is optimum, are judged. If the correction  
exposure information selected is judged not to be  
appropriate, the processing returns to step S1106, other  
correction exposure information is selected, and the same  
process as in steps S1107 and S1108 is repeated. If the  
corrected pattern is judged to be optimum in step S1109, the  
processing proceeds to step 110, the correction exposure  
information is established (S1110), and the evaluation is  
completed (S1111).

Here, during the processing shown in Fig. 11, it is  
preferable that the processing in relation to the judgement  
as to whether a correction is necessary, and the selection  
of the correction exposure information (S1104 and S1106) be  
performed; further, the evaluation of the corrected pattern,  
and the judgement as to whether the corrected pattern is  
optimum (S1108 and S1109), be judged by a visual inspection  
of an operator, and selected. These processings, however,

may be executed using an evaluating device performing the processing corresponding to each of the steps (steps S1104 and S1106, and steps S1108 and S1109).

Next, a description will be given of the procedure of correcting (calibrating) variations among the charged particles outputted from each element electron optical system.

Fig. 12 shows the procedure of performing a calibration of an element electron beam optical system. First, in step 1201, the optical axis of the irradiation light of the element electron beam optical system EL(i) to be corrected, is adjusted to the measuring position. The measuring position is provided on the stage 9 (Fig. 1), and is a position where the intensity of an irradiation light beam can be measured by a sensor 10.

Then, the intensity (irradiation dose) of the irradiation light from the element electron optical system EL(i) is measured, calibration data is determined, and whether the calibration data of all element electron optical systems have been determined is judged (S1208). If all data has not been determined (S1203-No), the optical axis is adjusted to the image forming position of the irradiation light from the next element electron optical system, the intensity (irradiation dose) is measured in the same manner with respect to the irradiation light which has formed the



image, and calibration data is determined (S1202).

If the calibration data of all of the element electron optical systems have been determined (S1203-Yes), the calibration data of the element electron optical systems is established (1204), and the results obtained are stored in the second correction factor memory 1030 shown in Fig. 10.

Fig. 13 shows the relationship of the drawing position ( $X_n$ ,  $Y_n$ ) with respect to the calibration data  $A(m)$  and the correction exposure information  $B(n, m)$ . Here, the drawing position is a coordinate component of the matrix constituting the element exposure field (EF) described with reference to Fig. 8, and is a unit which is subjected to an irradiation by charged particle beams. Reference numeral 1301 denotes the drawing position coordinate represented as a row matrix, and reference numerals 1302 and 1303 are correction exposure information each created under different conditions, and have a one-to-one correspondence with each component of the drawing position. Here, correction exposure information 1 (1302) and correction exposure information  $m$  (1303) are information stored in the first correction factor memory 1020 shown in Fig. 10, and the correction exposure information to be set is not common with respect to all element exposure fields (EF). The correction exposure information would be individually selected and set.

Calibration data 1305 is correction data corresponding

to each of the elements  $EL(1)$ ,  $EL(2)$ , ...,  $EL(m)$  of the element electron optical system 3, and are stored in the second correction factor memory 1030 shown in Fig. 10.

5 The calibration data 1305 and the correction exposure information (1302 and 1303) are data different in the cycle of correction during the irradiation of the charged particle beams. In the former one, a correction is performed when the system is activated with respect to the heating generated by the irradiation of the electron beams, or  
10 initial mechanical differences in the correction electron optical system 3 adjacent to the exposure system, and the cycle of the correction is one time to several times per day. On the other hand, in the latter one, since correction exposure information is uniquely determined for each drawing position, and a correction is performed for each irradiation  
15 position of charged particle beams, the frequency of the correction becomes enormous.

Thus, individually managing data differing in the correction cycle significantly facilitates the maintenance  
20 of data, for example, in that necessary data can be exclusively rewritten.

Furthermore, since the control of data using only necessary data can be performed in accordance with the use of correction, a required load of computation processing is  
25 reduced.

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Fig. 14 is a flowchart showing the processing of a data controller 1040 and a computing element 1050 (Fig. 10). In accordance with this flowchart, a description will be provided of the drawing of a corrected pattern considering the proximity effect correction for each irradiation position and the calibration of each of the element electron optical systems.

The data controller 1040 outputs the standard dose data which is stored in the basic dose data memory 1010 already created, to the computing element 1050 (S1401). Also, the data controller 1040 outputs the correction exposure information established in accordance with the evaluation procedure shown in Fig. 11, to the computing element 1050 (S1402).

The computing element 1050 first performs a proximity effect correction with respect to the standard dose data in accordance with the established correction exposure information (S1403). This correction is a change in duty for controlling the opening/closing of blankers. For example, when the duty of the standard dose data is "1.0", in accordance with the result of the correction, which increases the duty by 20%, the dose data after the correction is "1.2", while in accordance with the result of the correction which decreases the duty by 20%, the dose data after the correction is "0.8".

Next, in step 1404, the computing element 1050 judges whether the proximity effect correction has been completed, and if the processing of the correction has not yet been completed, step 1403 is carried on, while, if the processing of the correction has been completed with respect to all fields to be exposed, the data controller outputs the calibration data of each of the element electron optical systems established in accordance with the procedure shown in Fig. 12, to the computing element 1050 (S1405).

The computing element 1050 performs a correction considering calibration data with respect to data which has completed a proximity effect correction (S1406), and if the calibration data of all of the element electron optical systems is reflected to the correction (S1407-Yes), the processing proceeds to step S1308. If not so (S1407-No), the processing of step 1406 is carried on.

In step 1408, the computing element 1050 outputs corrected dose data, which has been subjected to the proximity effect correction for each irradiation position and the correction for each element electron optical system by calibration data, with respect to the standard dose data, to the drawing dose data memory 1060. Meanwhile, the drawing dose data memory 1060 serves as a kind of buffer, and is not an indispensable element in the embodiments in accordance with the present invention. The computing

element 1050, therefore, may output the corrected dose data to the driver 1070. The driver 1070 controls the opening/closing of the blankers in accordance with the corrected dose data (S1409).

5 In accordance with this embodiment, by selecting the correction exposure information performing a proximity effect correction for each irradiation position, and the calibration information for correcting variations in the irradiation dose among charged particles, it becomes possible to perform an exposure which has been subjected rapidly and appropriately to both corrections.

Moreover, by individually managing data differing in the correction cycle, the maintenance of data is significantly facilitated, for example, in that necessary data can be exclusively rewritten.

Furthermore, since the control of data using only necessary data can be performed in accordance with the use of correction, a required load of the computation processing can be reduced.

20 [Method for manufacturing a device]

Next, a description is given of embodiments of the method for manufacturing a device utilizing the electron beam exposure system 100 in accordance with the above-described embodiments.

25 Fig. 15 shows a flowchart of the manufacturing of a

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micro-device (e.g., a semiconductor chip such as IC and LSI, a liquid crystal panel, a CCD, a thin-film magnetic head, a micromachine, or the like). In step 1 (circuit design), the circuit design of a semiconductor device is performed. In step 2 (the creation of exposure control data), exposure control data for the exposure system is created in the computer 200 based on a circuit pattern. In step 3 (wafer manufacturing), a wafer is manufactured using a material such as silicon. In step 4 (wafer processing), which is referred to as a pre-process, an actual circuit is formed on a wafer by means of lithography, utilizing the electron beam exposure system 100 in which the exposure control data created in step 2 has been inputted. In the next step, step 5 (assembling), which is referred to as a post-process, the wafer manufactured in step 4 is formed into semiconductor chips. This process includes processes such as an assembling process (dicing and bonding) and a packaging process (enclosing of a chip). In step 6 (inspection), inspections such as an operation confirming test and a durability test are performed with respect to the device fabricated in step 5. Through such processes, semiconductor devices are produced, and are shipped (step 7).

Fig. 16 is a flowchart showing the particular flow of the wafer processing in the flowchart shown in Fig. 15. In step 11 (oxidation), the surface of the wafer is oxidized.

In step 12 (CVD), an insulating film is formed on the surface of the wafer. In step 13 (electrode formation), electrodes are formed on the wafer by deposition. In step 14 (ion implantation), ions are implanted onto the wafer. In step 15 (resist processing), a photosensitive agent is applied over the wafer. In step 16 (exposure), a circuit pattern is exposed and printed on the wafer using the electron beam system 100. In step 17 (development), the exposed wafer is developed. In step 18 (etching), portions except for the developed resist image are removed. In step 19 (stripping-off of resist), the resist, which became unnecessary as etching is over, is removed. By repeating these steps, circuit patterns are multiply formed on the wafer.

In accordance with the present invention, based on the correction exposure information appropriately selected and the calibration information for correcting variations in the irradiation light among charged particle beams, it is possible to expose a pattern on an object to be exposed, while controlling the irradiation light of the charged particle beams. Moreover, by individually managing data differing in the correction cycle, the maintenance of data is significantly facilitated, for example, in that necessary data can be exclusively rewritten. Furthermore, since the control of data using only necessary data can be performed

in accordance with the use of correction, a required load of computation processing can be reduced.

Except as otherwise disclosed herein, the various components shown in outline or in block form in the figures are individually well known and their internal construction and operation are not critical either to the making or using of this invention or to a description of the best mode of the invention.

While the present invention has been described with reference to what are presently considered to be the preferred embodiments, it is to be understood that the invention is not limited to the disclosed embodiments. On the contrary, the invention is intended to cover various modifications and equivalent arrangements included within the spirit and scope of the appended claims. The scope of the following claims is to be accorded the broadest interpretation so as to encompass all such modifications and equivalent structures and functions.

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WHAT IS CLAIMED IS:

1. A charged particle beam exposure system which draws a pattern on an object to be exposed by a plurality of charged particle beams, said system comprising:

(a) a storage device storing:

(i) standard dose data for controlling the irradiation of charged particle beams to an object to be exposed,

(ii) plural pieces of proximity effect correction data for correcting the irradiation of the charged particle beams for each incidence position with respect to the object to be exposed, in order to reduce the influence of a proximity effect; and

(iii) calibration data for correcting variations in the irradiation dose among a plurality of the charged particle beams; and

(b) a controller for controlling the irradiation of each of the charged particle beams, based on the standard dose data, the proximity effect correction data, and the calibration data.

2. A charged particle beam exposure system as claimed in claim 1, wherein the standard dose data includes bit map data which is determined depending on the pattern to be

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exposed.

3. A charged particle beam exposure system as claimed in claim 1, wherein the standard dose data includes the data defining the bit map data and a ratio of the irradiation time with respect to the non-irradiation time.

4. A charged particle beam exposure system as claimed in claim 1, further comprising obtaining means for obtaining the calibration data by measuring variations in the irradiation dose among a plurality of the charged particle beams.

5. A charged particle beam exposure system as claimed in claim 4, wherein said obtaining means includes a Faraday cup.

6. A charged particle beam exposure system as claimed in claim 1, further comprising selecting means for selecting one piece of data suitable for the proximity effect correction with respect to the standard dose data, from plural pieces of the proximity effect correction data stored in said memory device.

7. A method for correcting exposure data for drawing a

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pattern on an object to be exposed by a plurality of charged particle beams emitted from a plurality of element electron optical systems, said method comprising the steps of:

creating standard dose data for each irradiation position of the charged particle beams in order to expose a standard pattern on the object to exposed;

creating or renewing a plurality of the proximity effect correction data for each irradiation position, depending on conditions of the object to be exposed;

selecting any one piece of the proximity effect correction data, from plural pieces of the proximity effect correction data for each irradiation position;

performing a proximity effect correction with respect to the standard dose data based on the selected data, and exposing a pattern on the object to be exposed;

evaluating the exposed pattern, and judging whether the selected one piece of proximity effect correction data is the optimum data for controlling the standard dose data;

determining the optimum proximity effect correction data for controlling the standard dose data in accordance with the judgment;

measuring, by a sensor, the irradiation dose of the charged particle beams from each element electron optical system, the irradiation dose having been subjected to a correction by the proximity effect correction data; and

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determining the calibration data of each of the element electron optical systems, based on the irradiation dose measured in said measuring step.

8. A method for correcting exposure data as claimed in claim 7, wherein whether the selected one piece of proximity effect correction data is the optimum data for controlling the standard dose data is judged by comparing the exposed pattern and the standard pattern by a visual inspection.

9. A method for correcting exposure data as claimed in claim 7, wherein whether the selected one piece of proximity effect correction data is the optimum data for controlling the standard dose data is judged by evaluating means for comparing the exposed pattern and the standard pattern.

10. A method for correcting exposure data as claimed in claim 7, wherein the standard dose data includes bit map data which is determined depending on the pattern to be exposed.

11. A method for correcting exposure data as claimed in claim 7, wherein the standard dose data includes the data defining the bit map data and the ratio of the irradiation time with respect to the non-irradiation time.

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12. A method for correcting exposure data as claimed in claim 7, wherein the proximity effect correction data is data not depending on the pattern to be exposed, but depending on the conditions of the object to be exposed.

13. A method for correcting exposure data as claimed in claim 12, wherein the conditions are determined as at least one parameter among the fundamental conditions of the object to be exposed, the resist material, and a backward-scattering radius.

14. A method for correcting exposure data as claimed in claim 7, wherein the sensor in said measuring step includes a Faraday cup.

15. A method for manufacturing a device, comprising the steps of:

providing an exposure system as claimed in any one of claims 1 through 5;

exposing a pattern on a wafer using the exposure system; and

assembling a device by processing the wafer on which the pattern has been exposed.

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ABSTRACT OF THE DISCLOSURE

A charged particle beam exposure system which exposes a pattern on an object to be exposed, while controlling the irradiation light of charged particle beams, based on correction exposure information appropriately selected and calibration information for correcting variations in the irradiation light among the charged particle beams. This system includes (a) a storage device storing (i) standard dose data for controlling the irradiation of the charged particle beams to an object to be exposed, (ii) plural pieces of proximity effect correction data for correcting the irradiation of the charged particle beams for each incidence position with respect to the object to be exposed, in order to reduce the influence of a proximity effect, and (iii) calibration data for correcting variations in the irradiation dose among a plurality of the charged particle beams, and (b) a controller for controlling the irradiation of each of the charged particle beams, based on the standard dose data, the proximity effect correction data, and the calibration data.

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FIG. 1

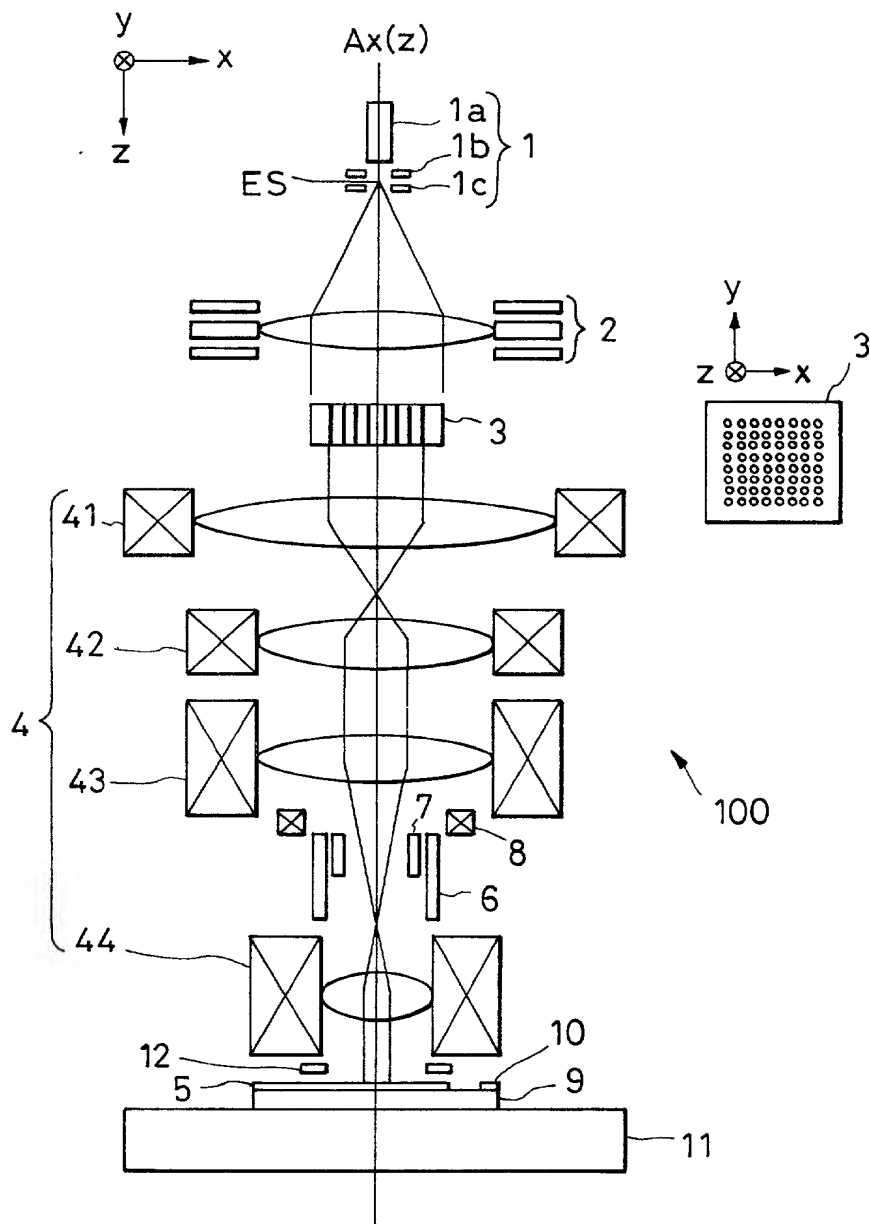


FIG. 2A

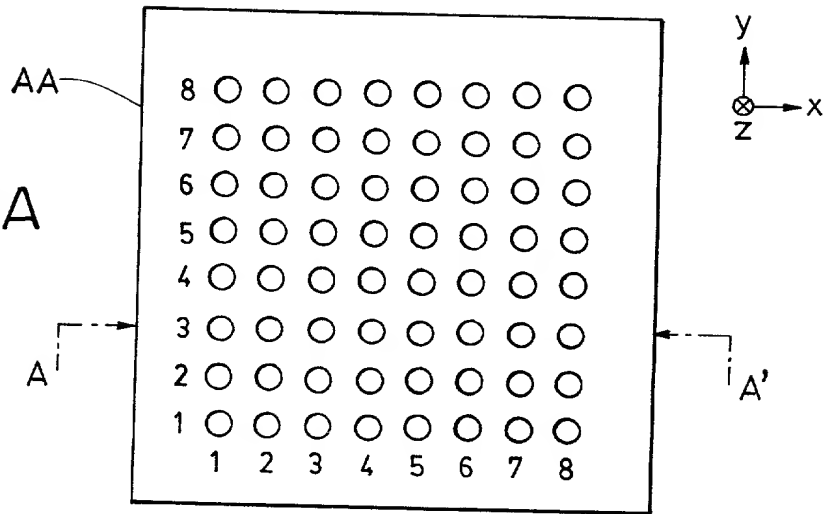


FIG. 2B

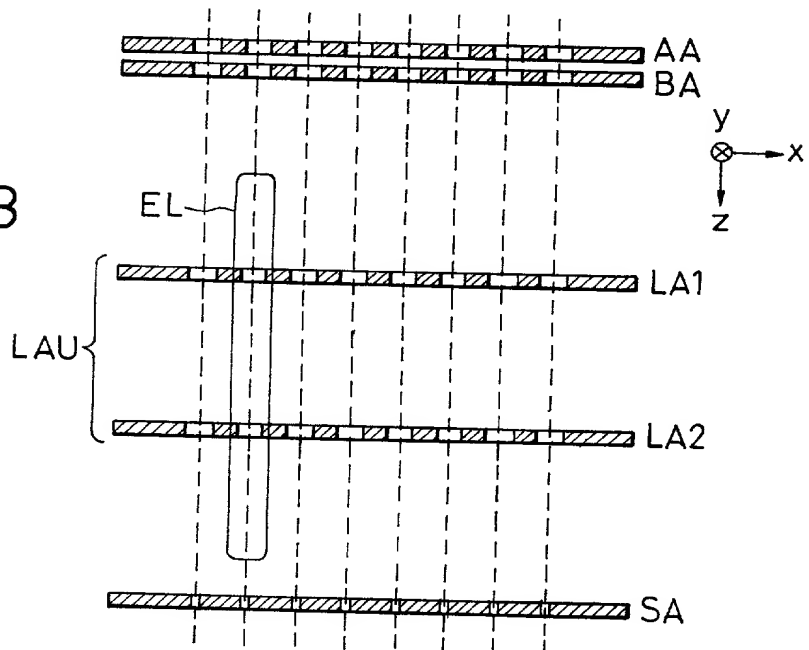




FIG. 3A

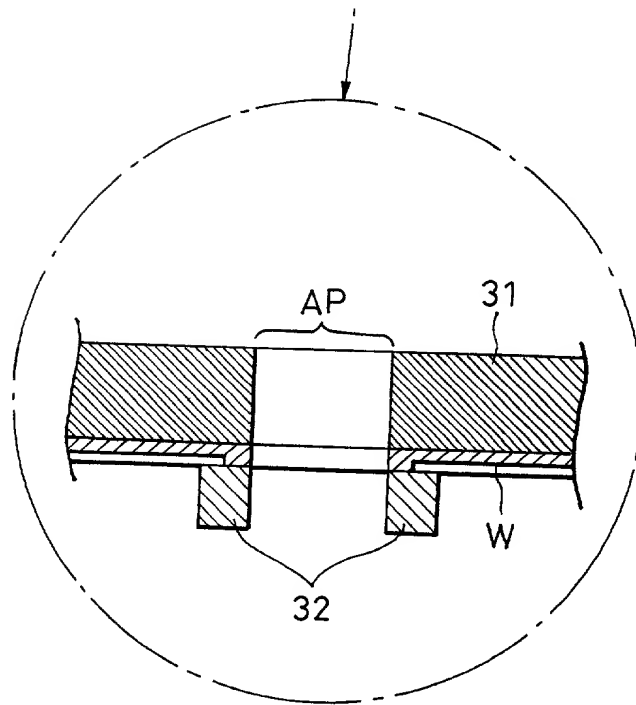
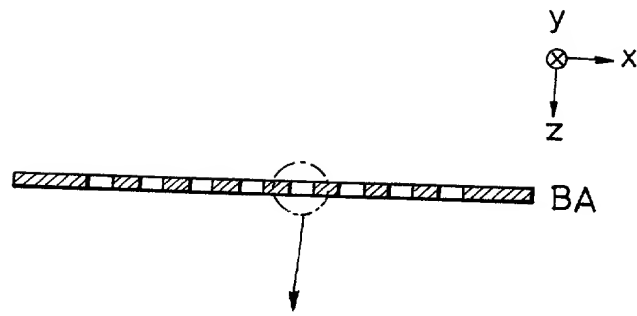


FIG. 3B

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FIG. 4

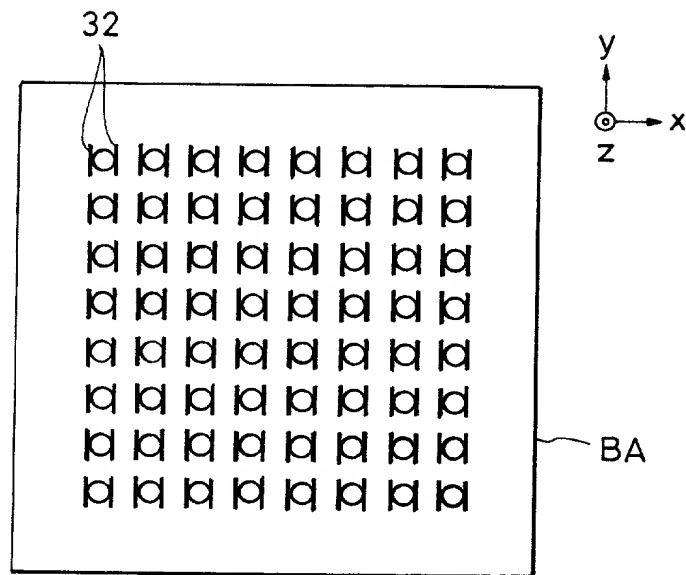
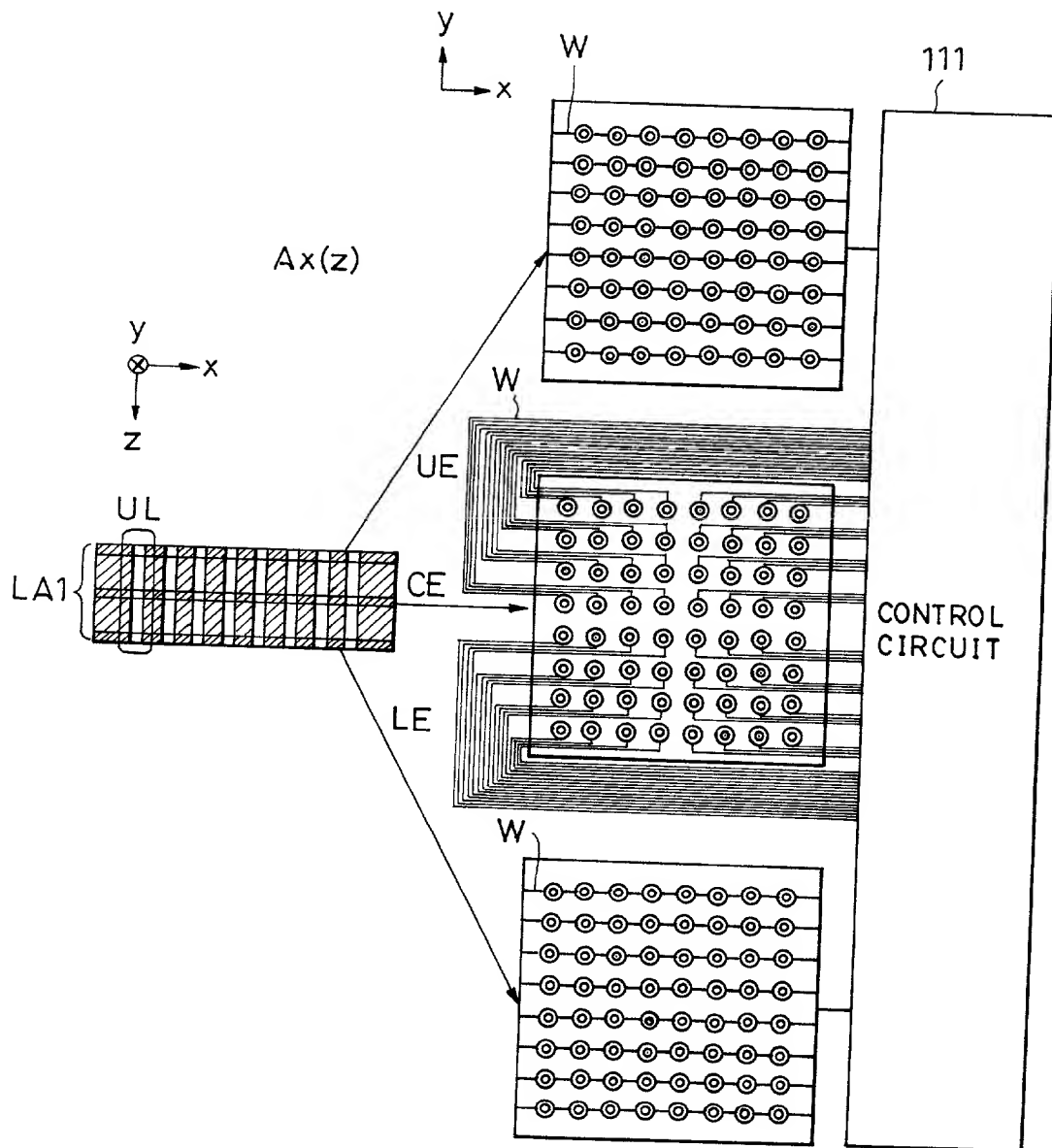
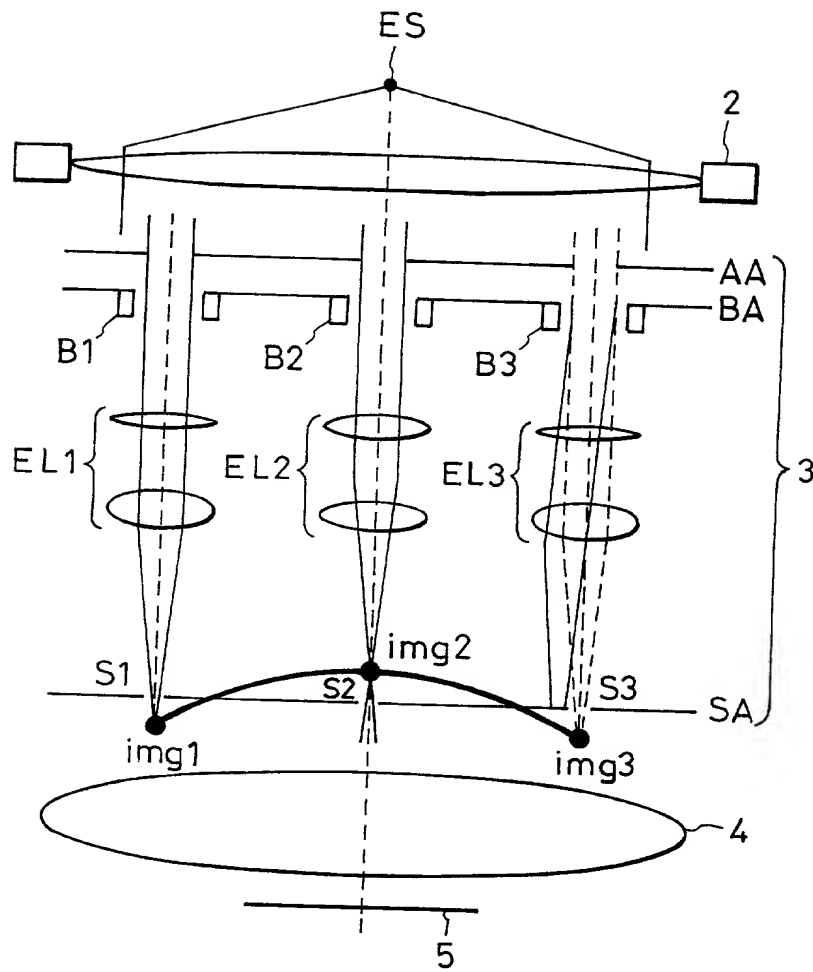


FIG. 5



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FIG. 6



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FIG. 7

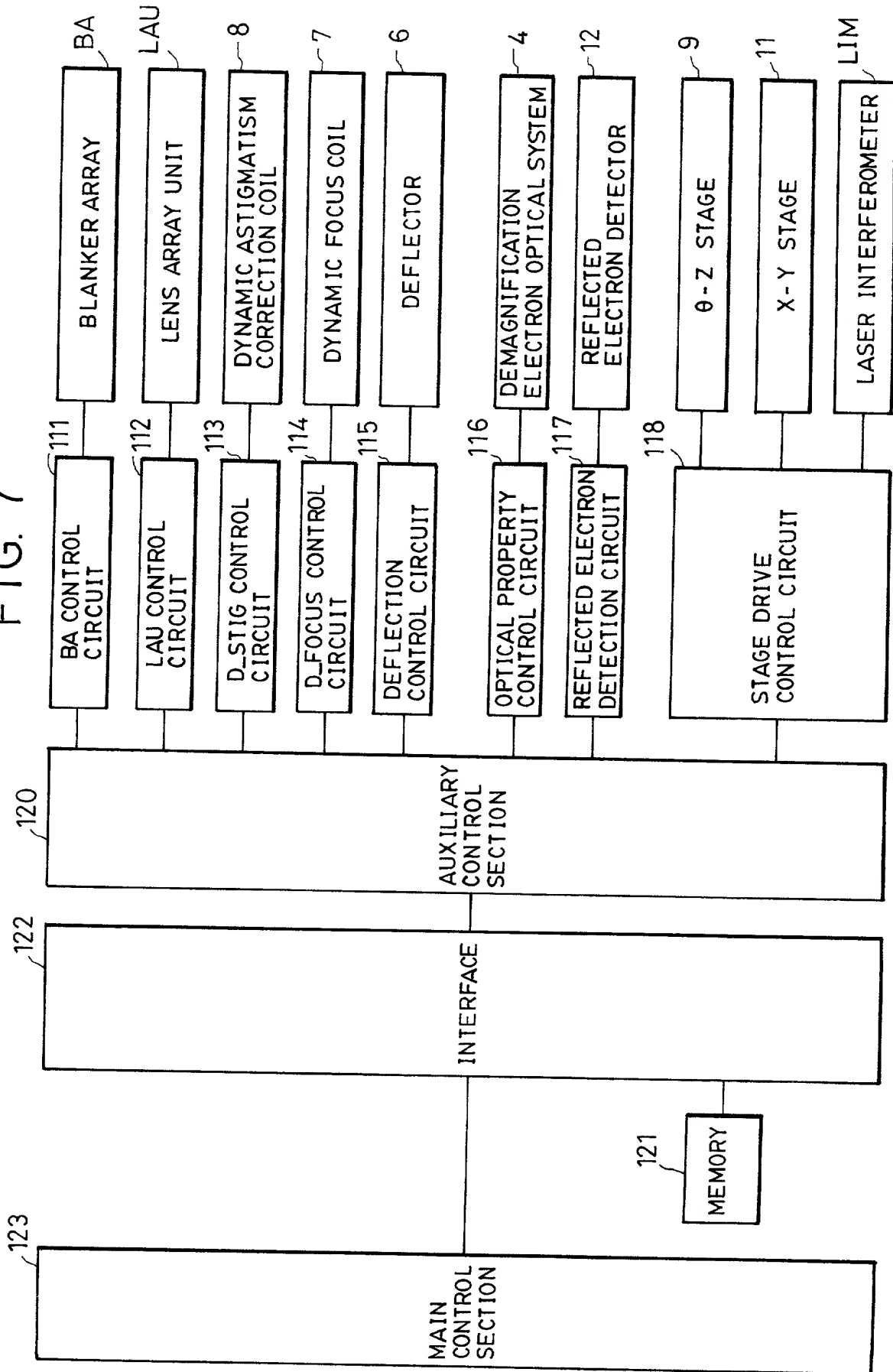


FIG. 8A

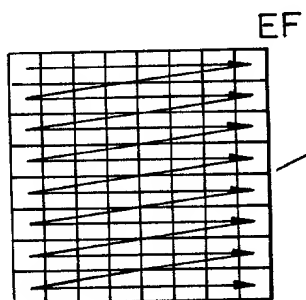


FIG. 8B

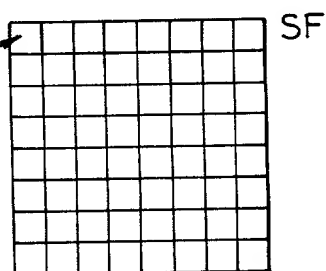


FIG. 8C

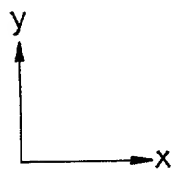
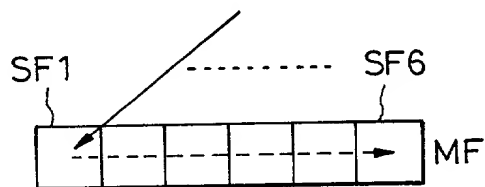


FIG. 8D

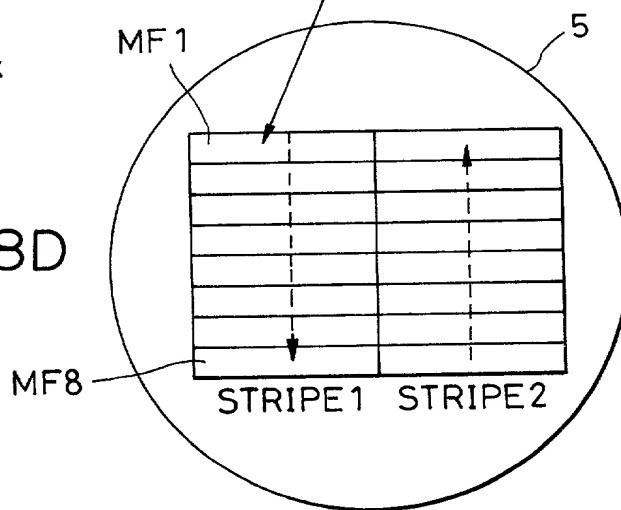


FIG. 9

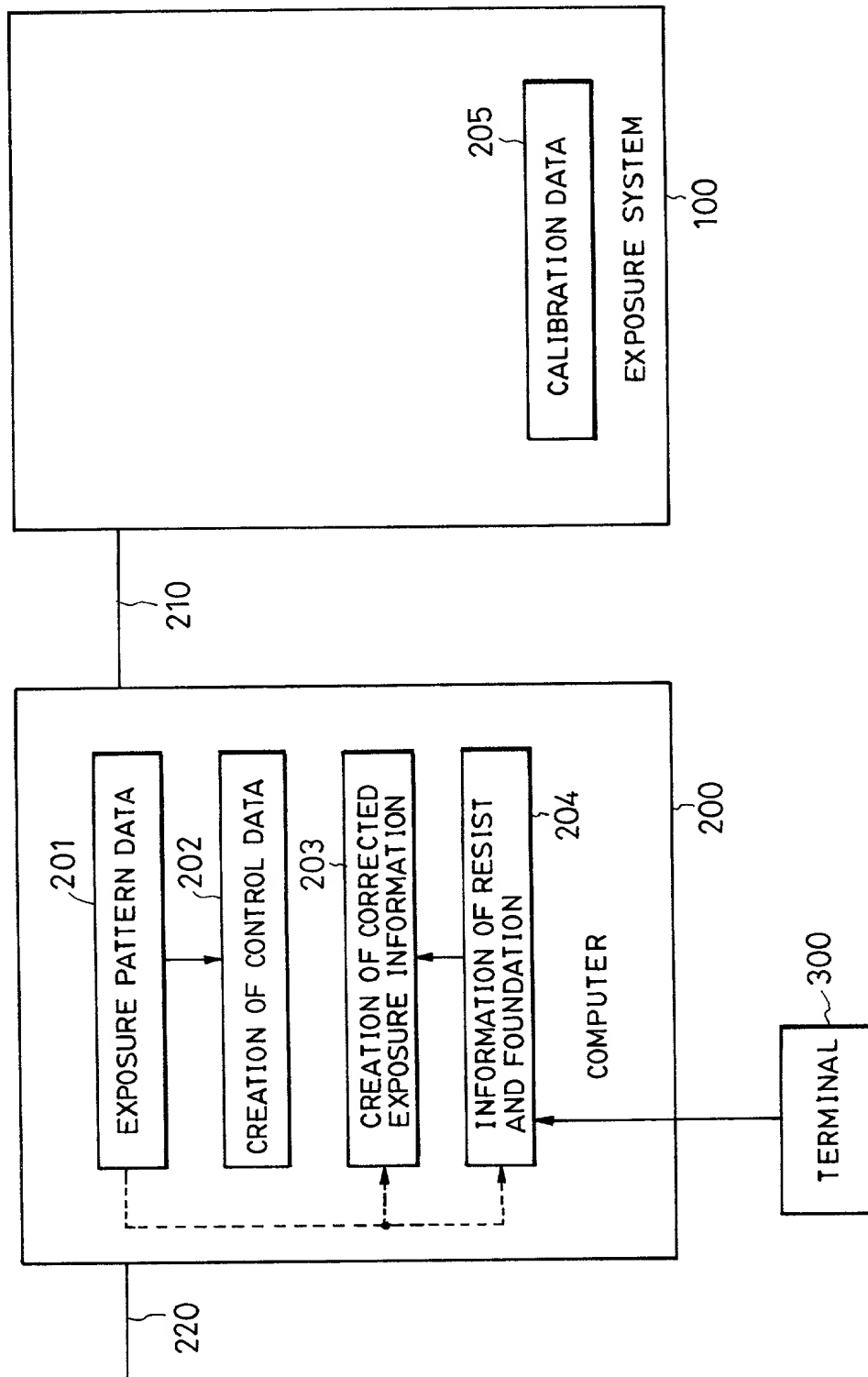


FIG. 10

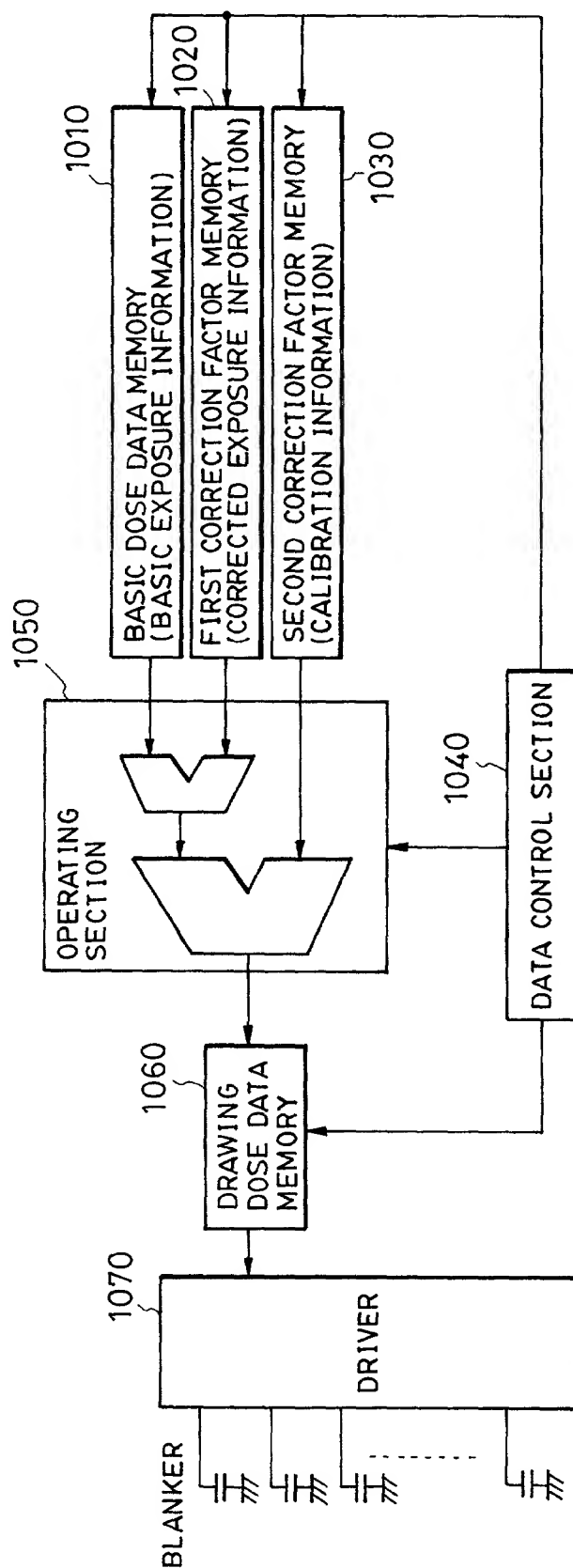
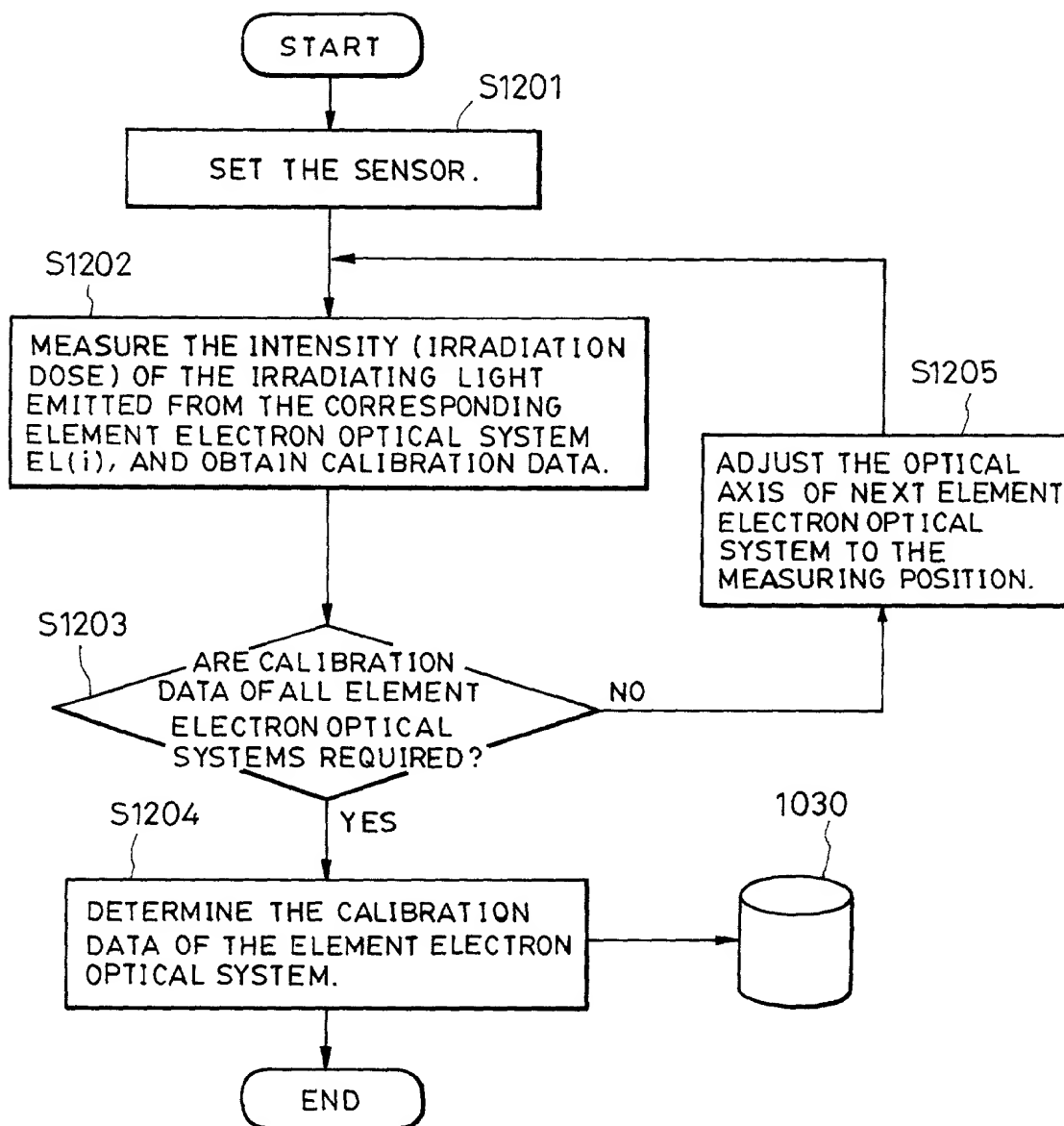






FIG. 12

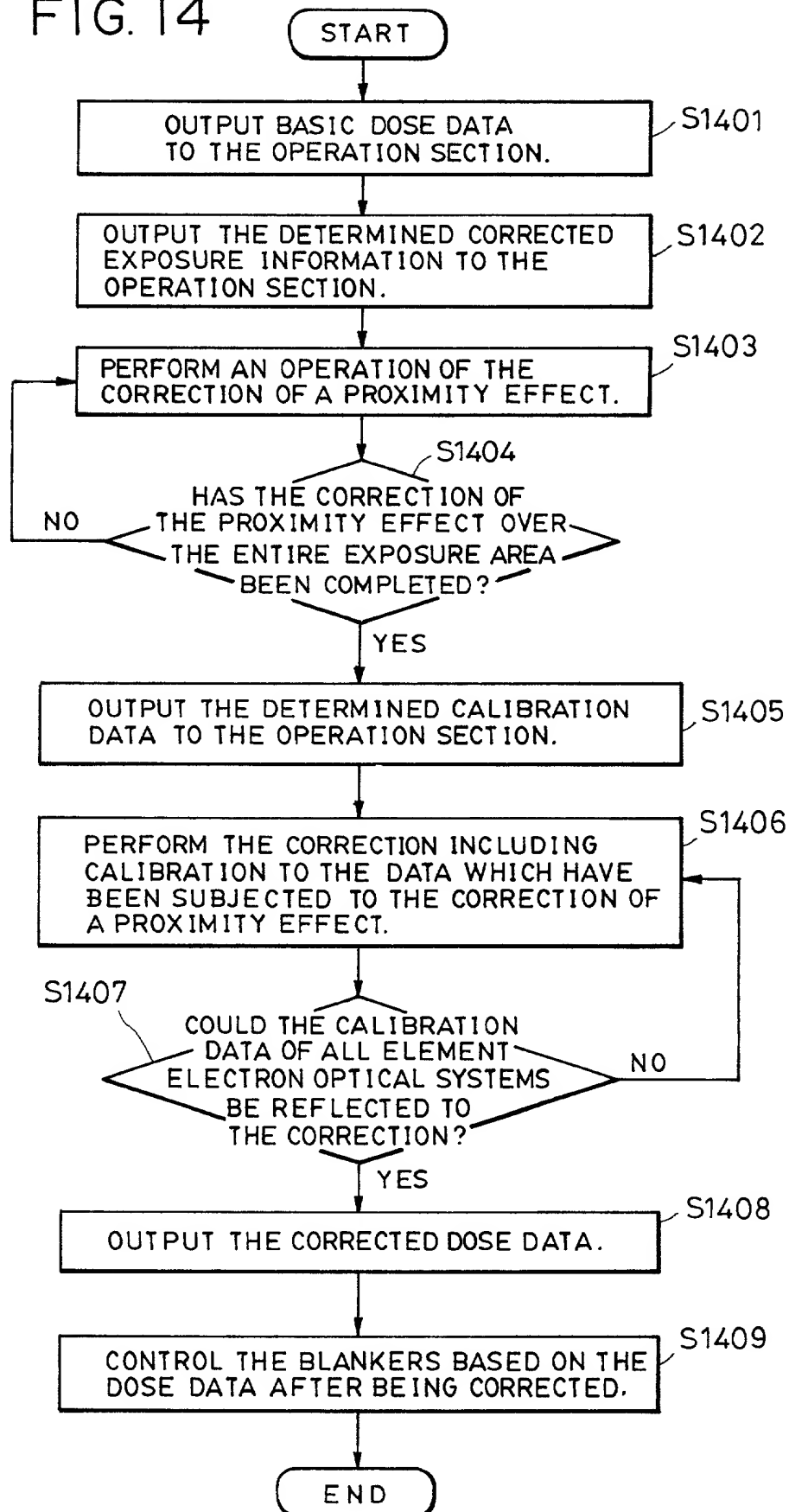


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FIG. 13

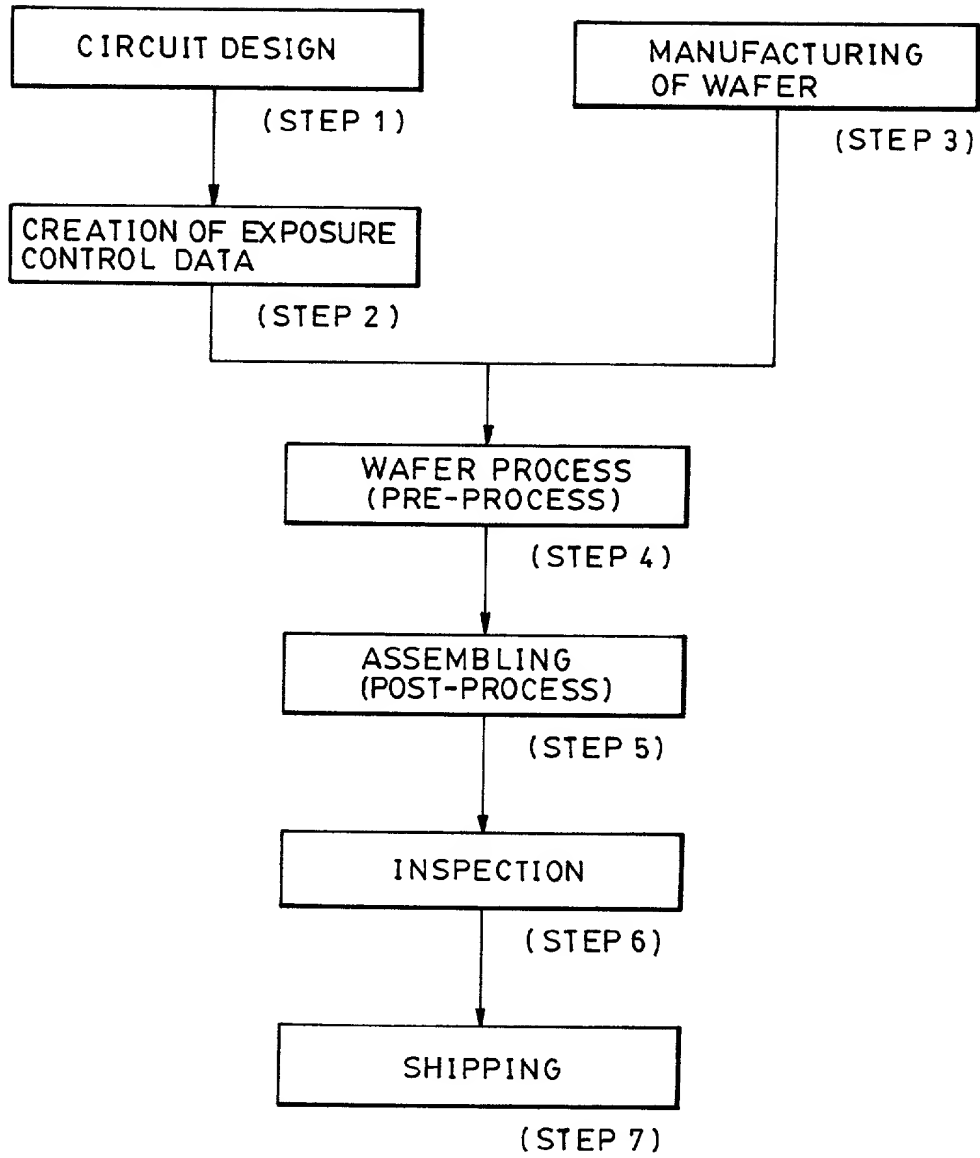
3	1302				
	ELEMENT ELECTRON OPTICAL SYSTEM	EL(1)	EL(2)	.....	EL(m)
1305	CALIBRATION DATA	A(1)	A(2)	.....	A(m)
	CORRECTED EXPOSURE INFORMATION DRAWING POSITION	CORRECTED EXPOSURE INFORMATION <sub>1</sub>	CORRECTED EXPOSURE INFORMATION <sub>2</sub>	.....	CORRECTION EXPOSURE INFORMATION <sub>m</sub>
1301	(X <sub>1</sub> , Y <sub>1</sub> )	B(1,1)	B(1,2)	.....	B(1,m)
	⋮	⋮	⋮	⋮	⋮
	⋮	⋮	⋮	⋮	⋮
	⋮	⋮	⋮	⋮	⋮
	⋮	⋮	⋮	⋮	⋮
	(X <sub>n</sub> , Y <sub>n</sub> )	B(n,1)	B(n,2)	.....	B(n,m)
1303					

FIG. 14



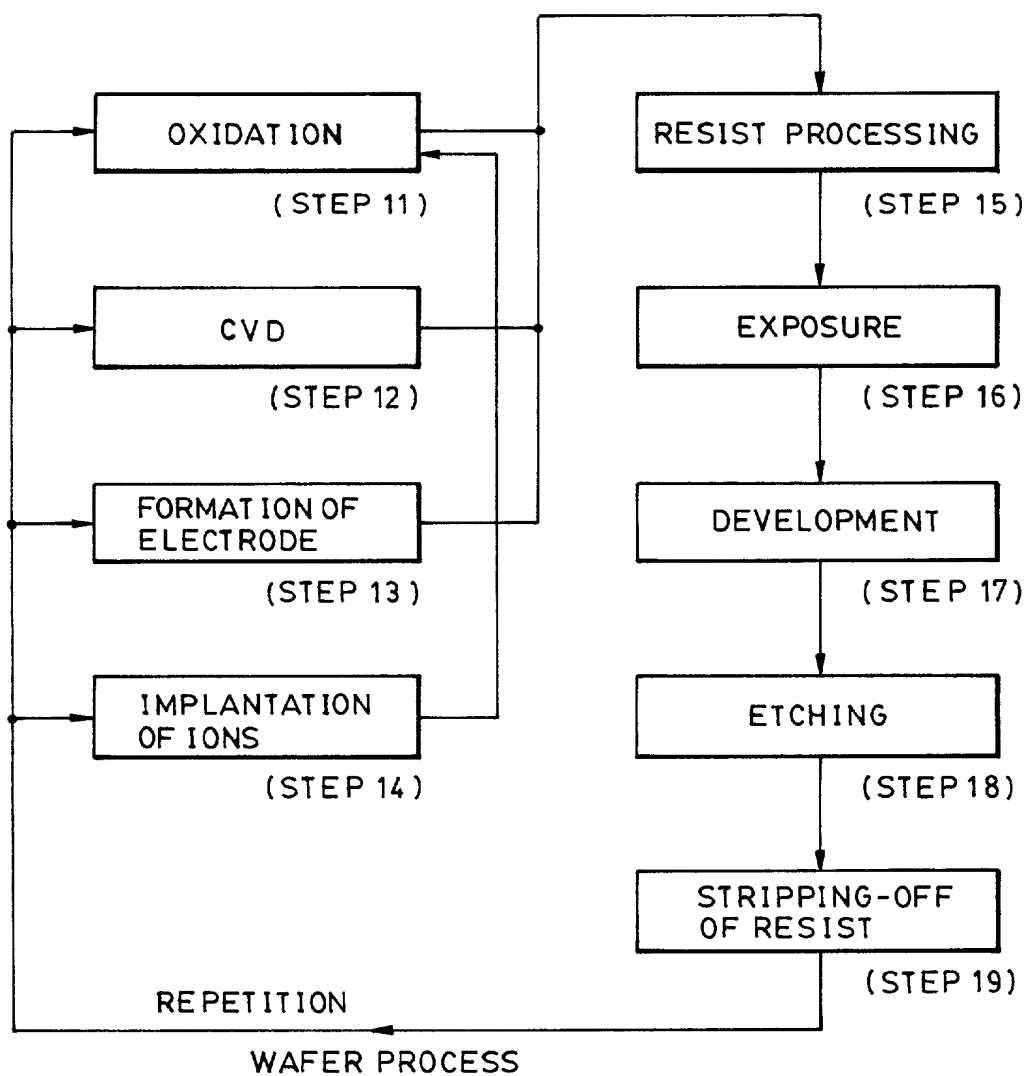
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FIG. 15



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FIG. 16



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**COMBINED DECLARATION AND POWER OF ATTORNEY  
FOR PATENT APPLICATION**  
(page 1)

As a below named inventor, I hereby declare that:

My residence, post office address and citizenship are as stated below next to my name;

I believe I am the original, first and sole inventor (if only one name is listed below) or an original, first and joint inventor (if plural names are listed below) of the subject matter which is claimed and for which a patent is sought on the invention entitled  
**CORRECTING METHOD FOR CORRECTING EXPOSURE DATA USED FOR A CHARGED PARTICLE  
BEAM EXPOSURE SYSTEM**

the specification of which ☒ is attached hereto. ☐ was filed on \_\_\_\_\_ as United States Application No. or PCT International Application No. \_\_\_\_\_ and was amended on \_\_\_\_\_ (if applicable).

I hereby state that I have reviewed and understand the contents of the above-identified specification, including the claims, as amended by any amendment referred to above.

I acknowledge the duty to disclose information which is material to patentability as defined in 37 CFR §1.56.

I hereby claim foreign priority benefits under 35 U.S.C. §119(a)-(d) or §365(b), of any foreign application(s) for patent or inventor's certificate, or §365(a) of any PCT international application which designates at least one country other than the United States, listed below and have also identified below any foreign application for patent or inventor's certificate, or PCT international application having a filing date before that of the application on which priority is claimed:

<u>Country</u>	<u>Application No.</u>	<u>Filed (Day / Mo. / Yr. )</u>	<u>( Yes / No ) Priority Claimed</u>
Japan	353484/1999 (Pat. )	13/December/1999	Yes

I hereby claim the benefit under 35 U.S.C. §120 of any United States application(s), or §365(c) of any PCT international application designating the United States, listed below and, insofar as the subject matter of each of the claims of this application is not disclosed in the prior United States or PCT international application in the manner provided by the first paragraph of 35 U.S.C. §112, I acknowledge the duty to disclose information which is material to patentability as defined in 37 C.F.R. §1.56 which became available between the filing date of the prior application and the national or PCT international filing date of this application.

<u>Application No.</u>	<u>Filed (Day/Mo./Yr.)</u>	<u>Status (Patented, Pending, Abandoned)</u>

I hereby appoint the practitioners associated with the firm and Customer Number provided below to prosecute this application and to transact all business in the Patent and Trademark Office connected therewith, and direct that all correspondence be addressed to the address associated with that Customer Number:

**FITZPATRICK, CELLA, HARPER & SCINTO**  
Customer Number: 05514

I hereby declare that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true; and further that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code and that such willful false statements may jeopardize the validity of the application or any patent issued thereon.

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